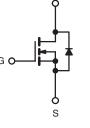
Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	800				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	1.2			
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Single				

TO-247 D



N-Channel MOSFET

FEATURES

- · Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- · Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRFPE50PbF
	SiHFPE50-E3
SnPb	IRFPE50
	SiHFPE50

ABSOLUTE MAXIMUM RATINGS T	c = 25 °C, u	nless otherw	vise noted				
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V _{DS}	800	v		
Gate-Source Voltage			V _{GS}	± 20			
Continuous Drain Current		T _C = 25 °C	1-	7.8			
		T _C = 100 °C	I _D	4.9	A		
Pulsed Drain Current ^a			I _{DM}	31	1		
Linear Derating Factor				1.5	W/°C		
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ		
Repetitive Avalanche Current ^a			I _{AR} 7.8		A		
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ		
Maximum Power Dissipation	T _C = 25 °C		PD	190	W		
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C			
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d	1		
Mounting Torque	6 22 or l	6-32 or M3 screw		10	lbf ⋅ in		
	0-32 OF IVIS SCIEW			1.1	N ⋅ m		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 23 mH, $R_G = 25 \Omega$, $I_{AS} = 7.8 \text{ A}$ (see fig. 12).

c. $I_{SD} \le 7.8$ A, dI/dt ≤ 140 A/µs, $V_{DD} \le 600$ V, $T_J \le 150$ °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply





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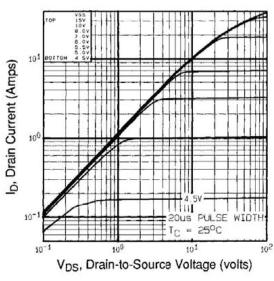
PARAMETER	SVMPOI	TVD	1	MAV			LINUT	
	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 40 0.24 - - 0.65			°C/W			
Case-to-Sink, Flat, Greased Surface Maximum Junction-to-Case (Drain)	R _{thCS}							
Maximum Junction-to-Case (Drain)	R _{thJC}	-						
SPECIFICATIONS T _J = 25 °C, u	unless otherv	vise noted						
PARAMETER	SYMBOL	TEST CONDITIONS			MIN.	TYP.	MAX.	UNI
Static								•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 25	i0 μA	800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D) = 1 mA	-	0.98	-	V/°0
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 25	50 µA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	,	-	-	± 100	nA
Zana Osta Mallana Daria Osmanl		V _{DS} =	V _{DS} = 800 V, V _{GS} = 0 V		-	-	100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 \	⁷ , V _{GS} = 0 V,	T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D =	4.7 A ^b	-	-	1.2	Ω
Forward Transconductance	g fs	V _{DS} =	100 V, I _D = 4	4.7 A ^b	5.6	-	-	S
Dynamic						•		
Input Capacitance	C _{iss}	<u> </u>		-	3100	-		
Output Capacitance	C _{oss}		$V_{GS} = 0 V,$ $V_{DS} = 25 V,$		-	800	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		fig. 5	-	490	-	
Total Gate Charge	Qg			-	-	200		
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		A, V _{DS} = 400 V, fig. 6 and 13 ^b	-	-	24	nC
Gate-Drain Charge	Q _{gd}		see lig.	o anu 15	-	-	110	
Turn-On Delay Time	t _{d(on)}		$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 7.8 \text{ A},$ $R_{G} = 6.2 \Omega, R_{D} = 52 \Omega$		-	19	-	ns
Rise Time	tr	V _{DD} =			-	38	-	
Turn-Off Delay Time	t _{d(off)}	R _G =			-	120	-	
Fall Time	t _f		see fig. 10 ^b		-	39	-	1
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	- nH	
Internal Source Inductance	L _S			-	13	-		
Drain-Source Body Diode Characteristic	s						1	
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol		-	-	7.8	
Pulsed Diode Forward Currenta	I _{SM}	integral reverse p - n junction diode		-	-	31	A	
Body Diode Voltage	V _{SD}	$T_{J} = 25 \text{ °C}, I_{S} = 7.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C, } I_{F} = 7.8 \text{ A,}$ dl/dt = 100 A/µs ^b		-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μΟ	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



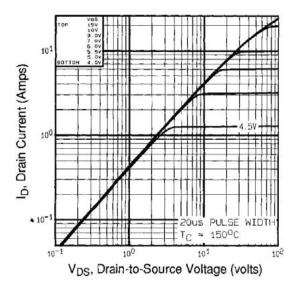


Fig. 2 - Typical Output Characteristics, $T_C = 150 \ ^\circ C$

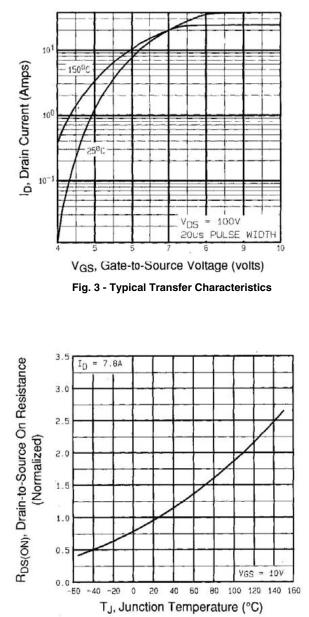


Fig. 4 - Normalized On-Resistance vs. Temperature

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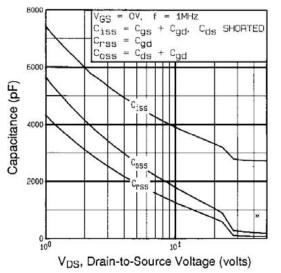


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

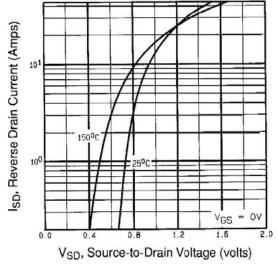


Fig. 7 - Typical Source-Drain Diode Forward Voltage

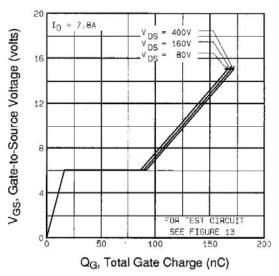
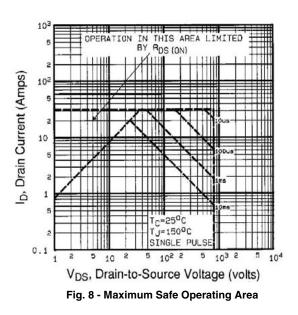


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





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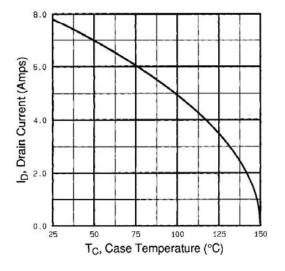


Fig. 9 - Maximum Drain Current vs. Case Temperature

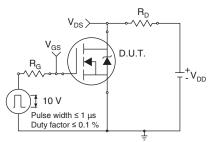


Fig. 10a - Switching Time Test Circuit

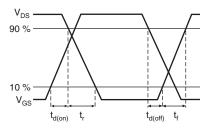


Fig. 10b - Switching Time Waveforms

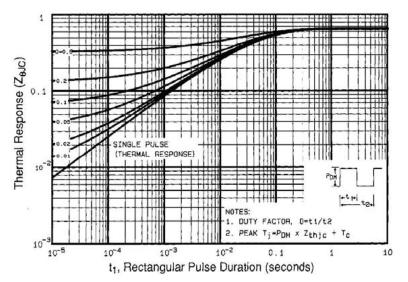


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

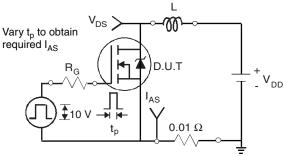


Fig. 12a - Unclamped Inductive Test Circuit

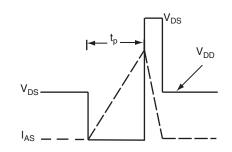


Fig. 12b - Unclamped Inductive Waveforms

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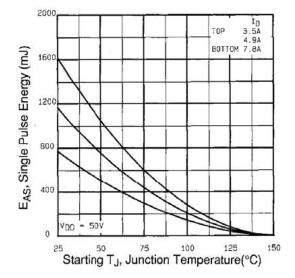
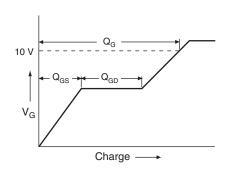


Fig. 12c - Maximum Avalanche Energy vs. Drain Current





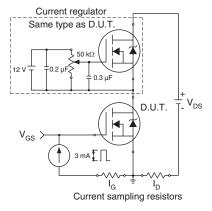
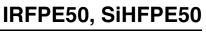
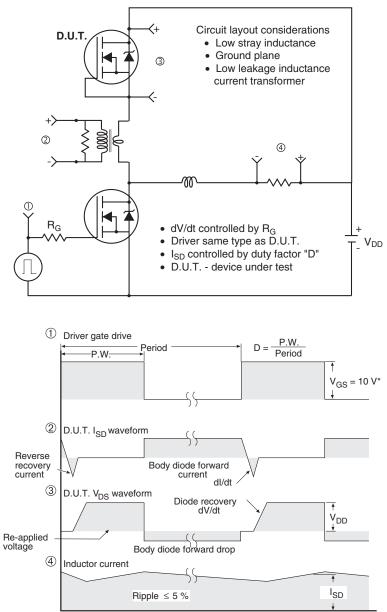


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit

* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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